



UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2829
Examiner: J. Hollington

In Re PATENT APPLICATION OF:

Applicant: Mikio OHTAKI

Appln. No.: 09/904,663

Filed: July 16, 2001

For: METHOD FOR MANUFACTURING
AND BATCH TESTING
SEMICONDUCTOR DEVICES

Atty Ref.: KAN 120D1

AMENDMENT

March 3, 2004

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450
Mail Stop RCE

Sir:

This Amendment is submitted with the Applicant's Request for Continued Examination (RCE) pursuant to 37 C.F.R. §1.114(a). The RCE is timely filed in response to the Final Office Action dated December 3, 2003. Prior to continued examination, please amend the above-referenced application as shown on the following pages.

FEE ENCLOSED: \$770
Please charge any further
fee to our Deposit Account
No. 18-0002.